AF/2800



MS AF
REPLY UNDER 37 C.F.R. § 1.116
EXPEDITED PROCEDURE
EXAMINING GROUP 2815

PATENT 3430-0131P

IN THE U.S. PATENT AND TRADEMARK OFFICE

Applicant:

HWANG, Kwang-Jo

Conf.:

5562

Appl. No.:

09/648,111

Group:

2815

Filed:

August 25, 2000

Examiner: Brock II, P.

For:

METHOD OF PATTERNING A METAL LAYER IN A

SEMICONDUCTOR DEVICE

LARGE ENTITY TRANSMITTAL FORM
FOR REPLY AFTER FINAL UNDER 37 C.F.R. § 1.116

MS AF

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

September 26, 2003

Sir:

Transmitted herewith is an amendment in the above-identified application.

The enclosed document is being transmitted via the Certificate of Mailing provisions of 37 C.F.R. § 1.8.

The enclosed document is being transmitted via facsimile.

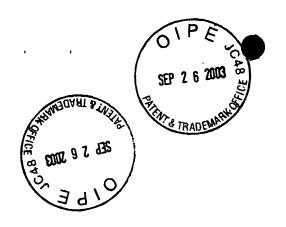
The fee has been calculated as shown below:

	CLAIMS REMAINING AFTER AMENDMENT		HIGHEST NUMBER PREVIOUSLY PAID FOR		PRESENT EXTRA	RATE	ADDITIONAL FEE
TOTAL	30	_	30	=	0	\$ 18	\$0.00
INDEPENDENT	4	_	4	=	0	\$ 84	\$0.00
FIRST PRESENTATION OF A MULTIPLE DEPENDENT CLAIM					\$280	\$0.00	
						TOTAL	\$0.00

Appl. No. 09/648,111

		nonth(s) extension of time pursuant to 1.136(a). \$0.00 for the extension of
\boxtimes	No fee is required.	
	Check(s) in the amount of	of \$0.00 is(are) enclosed.
	Please charge Deposit A \$0.00. This form is sub	Account No. 02-2448 in the amount of mitted in triplicate.
over requ:	urrent, and future repli payment to Deposit Accour	ssioner is hereby authorized in this, es, to charge payment or credit any nt No. 02-2448 for any additional fees 16 or 1.17; particularly, extension of
		Respectfully submitted,
		BIRCH, STEWART, KOLASCH & BIRCH, LLP
		By lette (1. Chon #40,953 WJoseph A. Kolasch, #22,463
	PLS/gf -0131P	P.O. Box 747 Falls Church, VA 22040-0747 (703) 205-8000
Atta	chment(s)	

(Rev. 04/30/03)



MS AF RESPONSE UNDER 37 CFR 1.116 EXPEDITED PROCEDURE EXAMINING GROUP 2815

PATENT 3430-0131P

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

APPLICANT(S):

HWANG, Kwang-Jo

CONF.:

5562

SERIAL NO.:

09/648,111

GROUP:

2815

FILED:

August 25, 2000

EXAMINER: BROCK II

FOR:

METHOD OF PATTERNING A METAL LAYER IN A

SEMICONDUCTOR DEVICE

AMENDMENT UNDER 37 C.F.R. 1.116

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450 September 26, 2603

Dear Sir:

In response to the final Office Action dated June 26, 2003, the following amendments and remarks are respectfully submitted in connection with the above-identified application.

This reply includes Amendments to the Claims and Remarks.